ISO 20903:2011-11 (E)

Surface chemical analysis - Auger electron spectroscopy and X-ray photoelectron spectroscopy - Methods used to determine peak intensities and information required when reporting results

Contents

Page

Foreword iv

Introduction v

1 Scope 1

2 Normative references 1

3 Terms and definitions 1

4 Symbols and abbreviated terms 1

5 Methods for peakintensity determination -- Direct spectrum 1
5.1 General 1
5.2 Selection and subtraction of an inelastic background 3
5.3 Measurement of peak intensity 3
5.4 Measurement of a peak intensity with computer software 4
5.5 Measurement of peak intensities for a spectrum with overlapping peaks 5
5.6 Uncertainty in measurement of peak area 5

6 Methods for peak intensity determination -- Augerelectron differential spectrum 6
6.1 General 6
6.2 Measurement of Augerelectron differential intensity 6
6.3 Uncertainties in measurement of Augerelectron differential intensity 7

7 Reporting of methods used to measure peak intensities 8
7.1 General requirements 8
7.2 Methods used to determine peak intensities in direct spectra 8
7.3 Methods used to obtain and determine peak intensities in Augerelectron differential spectra 9

Annex A (informative) Instrumental effects on measured intensities 10

Annex B (informative) Useful integration limits for determination of peak intensities in XPS spectra 11

Bibliography 13